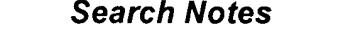


Search Notes 	Application/Control No. 09/908,943	Applicant(s)/Patent under Reexamination YAN ET AL.
	Examiner Jeff Lundgren	Art Unit 1639

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
stic seq search in interference database			STIC